

Search Notes**Application/Control No.**

10/626,668

Examiner

Peter Coughlan

Applicant(s)/Patent under Reexamination

PEACE, TERRENCE B.

Art Unit

2129

SEARCHED

Class	Subclass	Date	Examiner
700	1	5/19/2006	PDC
700	90	5/19/2006	PDC
706	1	5/19/2006	PDC
706	14	5/19/2006	PDC
706	45	5/19/2006	PDC
707	6	5/19/2006	PDC
128	898	5/19/2006	PDC
395	10	5/19/2006	PDC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East--groups, sets, clusters, compare, distribution, dimension, size, design w/ experiments, probability, specify, choose	5/19/2006	PDC
East---II--statistic, test, formula, algorithm, classify, Monte Carlo, random, linear, error, prediction, proximity	5/19/2006	PDC
East---III--percentage, threshold, data set, vector, input, code, keyboard, communication, computer,	5/19/2006	PDC
IEEE, vector, threshold, proximity, error, random, monte carlo, statistic, probability, design w/ experiments, dimension,	5/19/2006	PDC
IEEE--II--compare, sets, groups,	5/19/2006	PDC
Inventor Terrence B Peace	5/19/2006	PDC
707.6 with data w/dimensions, data w/probability distribution, data w/size 'M'	5/19/2006	PDC
128.898 with Monte Carlo, 95% confidence	5/19/2006	PDC